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PATENT NUMBER

U.S. UTILITY Patent Application

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APPLICATION NO. CONT/PRIOR CLASS SUBCLASS ART UNIT **EXAMINER** 09/942849 382 DF 2621 287 630

Moshe Finarov David Scheiner Avi Ravid

TITLE

Method and apparatus for monitoring a chemical mechanical planarization process applied to metal-based patterned objects

ISSUING CLASSIFICATION								
ORIGINAL			CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
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INTERNATIONAL CLASSIFICATION								
			Continued on Issue Slip Inside File Jacket					

TERMINAL				·	
DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
- DISCLAIMEN	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
The term of this patent				NOTICE OF ALLOWANCE MAILED	
subsequent to (date) has been disclaimed.	(Assistant Examiner)		(Date)	4,	
The term of this patent shall not extend beyond the expiration date					· e
of U.S Patent. No.	•			ISSUE FEE	
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(Rev. 6/99)

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